

DOCKET NO: 243329US2



IN THE UNITED STATES PATENT & TRADEMARK OFFICE

IN RE APPLICATION OF :
KENICHI KADOTA : EXAMINER: SUN, XIUQIN
SERIAL NO: 10/670,330 :
FILED: SEPTEMBER 26, 2003 : GROUP ART UNIT: 2863
FOR: SYSTEM FOR, METHOD OF AND :
COMPUTER PROGRAM PRODUCT FOR
DETECTING FAILURE OF
MANUFACTURING APPARATUSES

REQUEST TO RESET THE REPLY PERIOD BASED ON FAILURE TO RECEIVE

THE OFFICE ACTION MAILED ON JANUARY 21, 2005

COMMISSIONER FOR PATENTS
ALEXANDRIA, VIRGINIA 22313

SIR:

Applicants respectfully request that the Reply Period for the Office Action issued on January 21, 2005 on the above-referenced application be reset due to the fact that the Office Action presumably mailed by U.S. Patent and Trademark Office was never received by Applicants' Attorneys. The facts concerning this matter are as follows:

On June 2, 2005, a routine PAIR check on the status of this application revealed that on January 21, 2005 a non-final Office Action was issued, but never received. A copy of that Office Action obtained from PAIR is attached herewith as Exhibit A. This Office Action has been logged in our firm's docketing system on the same day it was discovered, as shown in the enclosed printout from our docketing system (Exhibit B).

In our firm, all mail received from the Patent Office is opened and logged in a daily computer mail log and the due date is entered in a firm computer docketing system. At the

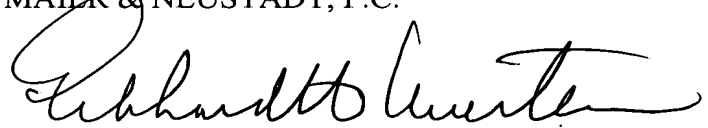
Application No. 10/670,330
Request to re-set the Office Action date

time of entry into the computer, the serial numbers are checked to ensure that the correct docket number appears on the mail so that the documents are entered in the correct application in the computer and matched with the correct application file. Any due dates resulting from the Patent and Trademark Office mail are also entered in the computer. A copy of our PTO Mail Log Report containing entries from January 21, 2005 to February 4, 2005 is enclosed herein as Exhibit C. A detailed search in our docketing system indicates that the Office Action mailed on January 21, 2005 was never received in our office.

Based on the above-summarized facts and the provisions of MPEP § 710.06, the reset of the reply period for the Office Action mailed on January 21, 2005 is earnestly solicited.

Respectfully submitted,

OBLON, SPIVAK, McCLELLAND,
MAIER & NEUSTADT, P.C.



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22850

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EHK/MQM/kkn

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Docket No.: 243329US2

COMMISSIONER FOR PATENTS
ALEXANDRIA, VIRGINIA 22313

RE: Application Serial No.: 10/670,330

Applicants: Kenichi KADOTA

Filing Date: September 26, 2003

For: SYSTEM FOR, METHOD OF AND COMPUTER
PROGRAM PRODUCT FOR DETECTING FAILURE
OF MANUFACTURING APPARATUSES

Group Art Unit: 2863

Examiner: SUN, XIUZIN

SIR:

Attached hereto for filing are the following papers:

**REQUEST TO RESET THE REPLY PERIOD BASED ON FAILURE TO RECEIVE THE
OFFICE ACTION MAILED ON JANUARY 21, 2005**

**OFFICE ACTION DATED JANUARY 21, 2005 OBTAINED FROM PAIR (Exhibit A)
DOCKETING SYSTEM PRINTOUT (Exhibit B)**

**COPY OF OUR PTO MAIL LOG REPORT CONTAINING ENTRIES FROM JANUARY 21,
2005 TO FEBRUARY 4, 2005 (Exhibit C)**

In the event any variance exists between the amount enclosed and the Patent Office charges for filing the above-noted documents, including any fees required under 37 C.F.R. 1.136 for any necessary Extension of Time to make the filing of the attached documents timely, please charge or credit the difference to our Deposit Account No. 15-0030. Further, if these papers are not considered timely filed, then a petition is hereby made under 37 C.F.R. 1.136 for the necessary extension of time. A duplicate copy of this sheet is enclosed.

Respectfully submitted,

OBLON, SPIVAK, McCLELLAND,
MAIER & NEUSTADT, P.C.

Eckhard H. Kuesters

Registration No. 28,870

Customer Number

22850

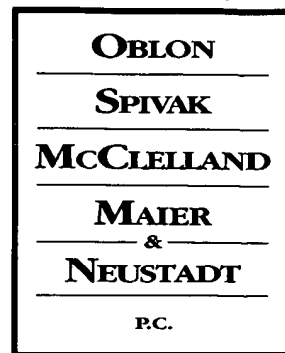
(703) 413-3000 (phone)

(703) 413-2220 (fax)

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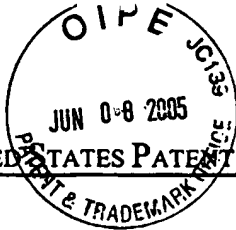


Exhibit A

UNITED STATES PATENT AND TRADEMARK OFFICE

UNITED STATES DEPARTMENT OF COMMERCE
United States Patent and Trademark Office
Address: COMMISSIONER FOR PATENTS
P.O. Box 1450
Alexandria, Virginia 22313-1450
www.uspto.gov

APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/670,330	09/26/2003	Kenichi Kadota	243329US2	5106
22850	7590	01/21/2005		
OBLON, SPIVAK, MCCLELLAND, MAIER & NEUSTADT, P.C. 1940 DUKE STREET ALEXANDRIA, VA 22314			EXAMINER SUN, XIUQIN	
			ART UNIT 2863	PAPER NUMBER
DATE MAILED: 01/21/2005				

Please find below and/or attached an Office communication concerning this application or proceeding.

RECEIVED: 6205 MAIR PAIR PAIR out
OBLON, SPIVAK, McCLELLAND
MAIER & NEUSTADT, P.C.
DOCKETING DEPT
Initials/Date Docketed: 6205
Type of Resp(s): 6205
Due Date(s): 6-21-05

Office Action Summary	Application No. 10/670,330	Applicant(s) KADOTA, KENICHI	
	Examiner Xiuqin Sun	Art Unit 2863	

-- The MAILING DATE of this communication appears on the cover sheet with the correspondence address --

Period for Reply

A SHORTENED STATUTORY PERIOD FOR REPLY IS SET TO EXPIRE 3 MONTH(S) FROM THE MAILING DATE OF THIS COMMUNICATION.

- Extensions of time may be available under the provisions of 37 CFR 1.136(a). In no event, however, may a reply be timely filed after SIX (6) MONTHS from the mailing date of this communication.
 - If the period for reply specified above is less than thirty (30) days, a reply within the statutory minimum of thirty (30) days will be considered timely.
 - If NO period for reply is specified above, the maximum statutory period will apply and will expire SIX (6) MONTHS from the mailing date of this communication.
 - Failure to reply within the set or extended period for reply will, by statute, cause the application to become ABANDONED (35 U.S.C. § 133).
- Any reply received by the Office later than three months after the mailing date of this communication, even if timely filed, may reduce any earned patent term adjustment. See 37 CFR 1.704(b).

Status

- 1) ☐ Responsive to communication(s) filed on 26 September 2003.
- 2a) ☐ This action is FINAL. 2b) ☒ This action is non-final.
- 3) ☐ Since this application is in condition for allowance except for formal matters, prosecution as to the merits is closed in accordance with the practice under *Ex parte Quayle*, 1935 C.D. 11, 453 O.G. 213.

Disposition of Claims

- 4) ☒ Claim(s) 1-20 is/are pending in the application.
- 4a) Of the above claim(s) _____ is/are withdrawn from consideration.
- 5) ☐ Claim(s) _____ is/are allowed.
- 6) ☒ Claim(s) 1,5,6,9,12,13,15,18 and 19 is/are rejected.
- 7) ☒ Claim(s) 2-4,7,8,10,11,14,16,17 and 20 is/are objected to.
- 8) ☐ Claim(s) _____ are subject to restriction and/or election requirement.

Application Papers

- 9) ☐ The specification is objected to by the Examiner.
- 10) ☒ The drawing(s) filed on 26 September 2003 is/are: a) ☒ accepted or b) ☐ objected to by the Examiner.
Applicant may not request that any objection to the drawing(s) be held in abeyance. See 37 CFR 1.85(a).
Replacement drawing sheet(s) including the correction is required if the drawing(s) is objected to. See 37 CFR 1.121(d).
- 11) ☐ The oath or declaration is objected to by the Examiner. Note the attached Office Action or form PTO-152.

Priority under 35 U.S.C. § 119

- 12) ☒ Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f).
- a) ☒ All b) ☐ Some * c) ☐ None of:
1. ☐ Certified copies of the priority documents have been received.
2. ☐ Certified copies of the priority documents have been received in Application No. _____.
3. ☐ Copies of the certified copies of the priority documents have been received in this National Stage application from the International Bureau (PCT Rule 17.2(a)).

* See the attached detailed Office action for a list of the certified copies not received.

Attachment(s)

- | | |
|---|---|
| 1) <input checked="" type="checkbox"/> Notice of References Cited (PTO-892) | 4) <input type="checkbox"/> Interview Summary (PTO-413)
Paper No(s)/Mail Date. _____ |
| 2) <input type="checkbox"/> Notice of Draftsperson's Patent Drawing Review (PTO-948) | 5) <input type="checkbox"/> Notice of Informal Patent Application (PTO-152) |
| 3) <input checked="" type="checkbox"/> Information Disclosure Statement(s) (PTO-1449 or PTO/SB/08)
Paper No(s)/Mail Date <u>09/26/2003</u> . | 6) <input type="checkbox"/> Other: _____ |

DETAILED ACTION

Claim Rejections - 35 USC § 103

1. The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:

(a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negated by the manner in which the invention was made.

2. Claims 1, 5, 6, 9, 12, 13, 15, 18 and 19 are rejected under 35 U.S.C. 103(a) as being unpatentable over Morioka et al. (U.S. Pat. No. 5274434) in view of Chen et al. (U.S. Pat. No. 5726920).

In regard to claims 1, 9 and 15:

Morioka et al. teach a system, method and computer program product for detecting failure of manufacturing apparatuses, comprising: a low-yield detecting portion which identifies a low-yield-period apparatus having a significantly lower yield period compared with other manufacturing apparatus and the significantly lower yield period by comparing yields of a plurality of manufacturing apparatuses used in parallel in a specific manufacturing process for each time period when the manufacturing apparatuses were used (col. 4, lines 26-53; col. 6, lines 1-40; col. 12, lines 1-29 and lines 50-58 and col. 17, lines 17-30); a warning issuing portion which issues multi-level warnings to the low-yield-period apparatus and the downward-tendency apparatus (col.

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7, lines 17-41; col. 12, lines 62-67; col. 13, lines 1-13 and col. 15, lines 4-28); and a yield data storing portion which stores yield data of the plurality of manufacturing apparatuses for each time period when the manufacturing apparatuses were used (col. 14, lines 32-67; col. 15, lines 1-3 and col. 15, lines 4-28).

Morioka et al. do not mention explicitly: a downward-tendency detecting portion which identifies a downward-tendency apparatus having a significant downward tendency in yield compared with the other manufacturing apparatus by comparing recent yield trends of the plurality of manufacturing apparatuses.

Chen et al. teach a mass-production style semiconductor wafer testing system and method, including: a downward-tendency detecting portion which identifies a downward-tendency apparatus having a significant downward tendency in yield compared with the other manufacturing apparatus by comparing recent yield trends of the plurality of manufacturing apparatuses (col. 26, lines 26-44 and lines 56-67; col. 27, lines 1-15; col. 28, lines 50-67 and col. 29, lines 1-23).

It would have been obvious to one having ordinary skill in the art at the time the invention was made to include the teaching of Chen et al. in the invention of Morioka et al. in order to provide a mechanism for monitoring the trend of deteriorations in production-lines and predicting possible failure of manufacturing apparatuses (Chen et al., col. 26, lines 56-67 and col. 27, lines 1-15).

In regard to claims 5, 12 and 18:

Morioka et al. teach the subject matter discussed above. Morioka et al. do not mention explicitly: a trend threshold determining portion which detects one of the

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manufacturing apparatuses which has a downward tendency in recent yield trend compared with a yield-trend threshold value; and a downward-tendency identifying portion which identifies one of the manufacturing apparatuses which has a significant difference in recent yield trend from the other manufacturing apparatus as the downward-tendency apparatus.

The teachings of Chen et al. include: a trend threshold determining portion which detects one of the manufacturing apparatuses which has a downward tendency in recent yield trend compared with a yield-trend threshold value ; and a downward-tendency identifying portion which identifies one of the manufacturing apparatuses which has a significant difference in recent yield trend from the other manufacturing apparatus as the downward-tendency apparatus (col. 28, lines 50-67 and col. 29, lines 1-22).

It would have been obvious to one having ordinary skill in the art at the time the invention was made to include the teaching of Chen et al. in the invention of Morioka et al. in order to provide an effective mechanism for monitoring the trend of deteriorations in production-lines and predicting failure of manufacturing apparatuses (Chen et al., col. 26, lines 56-67 and col. 27, lines 1-15).

In regard to claims 6, 13 and 19:

Morioka et al. teach the subject matter discussed above. Morioka et al. do not mention explicitly: the warning issuing portion issues the warnings of levels depending on whether or not the significantly lower yield period of the low-yield-period apparatus is

currently continuing, and whether or not the low-yield-period apparatus has a significant downward tendency in yield compared with the other manufacturing apparatus.

The teachings of Chen et al. include: the warning issuing portion issues the warnings of levels depending on whether or not the significantly lower yield period of the low-yield-period apparatus is currently continuing, and whether or not the low-yield-period apparatus has a significant downward tendency in yield compared with the other manufacturing apparatus (col. 16, lines 57-67 and col. 17, lines 1-44).

It would have been obvious to one having ordinary skill in the art at the time the invention was made to include the teaching of Chen et al. in the invention of Morioka et al. in order to provide an effective mechanism for predicting failures of manufacturing apparatuses through which respective alarm condition can be defined and issued in levels depending on the severity of the failure (Chen et al., col. 16, lines 57-67 and col. 17, lines 1-44).

Allowable Subject Matter

3. Claims 2-4, 7, 8, 10, 11, 14, 16, 17 and 20 are objected to as being dependent upon a rejected base claim, but would be allowable if rewritten in independent form including all of the limitations of the base claim and any intervening claims.

Reasons for Allowance

4. The following is an examiner's statement of reasons for allowance:

The primary reason for the allowance of claims 2-4 is the inclusion of the claimed method step of: a low-yield identifying portion which identifies one of the manufacturing apparatuses having a significant difference in yield from the other manufacturing apparatus during the low yield period as the low-yield-period apparatus, and identifies the low yield period as being the significantly lower yield period. It is this limitation found in each of the claims, as it is claimed in the combination that has not been found, taught or suggested by the prior art of record, which makes these claims allowable over the prior art.

The primary reason for the allowance of claims 7, 14 and 20 is the inclusion of the limitation of an event/operation condition examining portion which examines whether or not maintenance, inspection, repair or component replacement was performed on the low-yield-period apparatus and whether or not operating conditions for the low-yield-period apparatus have been changed before and after the significantly lower yield period identified by the low-yield detecting portion. It is this limitation found in each of the claims, as it is claimed in the combination that has not been found, taught or suggested by the prior art of record, which makes these claims allowable over the prior art.

The primary reason for the allowance of claim 8 is the inclusion of the limitation that said yield data includes at least one of a good product rate of finished products having experienced a series of manufacturing processes including the specific manufacturing process, a good product rate in the specific manufacturing process, a characteristic quantity representing in number a distribution of defectives in a wafer

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surface of a semiconductor wafer processed by one of the manufacturing apparatuses as a processed object, and a characteristic quantity representing in number a distribution of yields in one lot of a group of objects processed by one of the manufacturing apparatuses. It is this limitation found in the claim, as it is claimed in the combination that has not been found, taught or suggested by the prior art of record, which makes this claim allowable over the prior art.

The primary reason for the allowance of claims 10 and 11 is the inclusion of the claimed method step of identifying one of the manufacturing apparatuses having a significant difference in yield from the other manufacturing apparatus during the low yield period as the low-yield-period apparatus, and identifying the low yield period as being the significantly lower yield period. It is this limitation found in each of the claims, as it is claimed in the combination that has not been found, taught or suggested by the prior art of record, which makes these claims allowable over the prior art.

The primary reason for the allowance of claims 16 and 17 is the inclusion of the limitation of an instruction configured to identify one of the manufacturing apparatuses having a significant difference in yield from the other manufacturing apparatus during the low yield period as the low-yield-period apparatus, and identify the low yield period as being the significantly lower yield period. It is this limitation found in each of the claims, as it is claimed in the combination that has not been found, taught or suggested by the prior art of record, which makes these claims allowable over the prior art.

Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably

accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

Prior Art Citations

5. The prior art made of record and not relied upon is considered pertinent to applicant's disclosure.

1) Morioka et al. (U. S. Pat. No. 6611728) is entitled "Inspection system and method for manufacturing electronic devices using the inspection system".

2) Ono et al. (U. S. Pub. No. 20020143483) is entitled "Inspection system, inspection apparatus, inspection program, and production method of semiconductor devices".

3) Yoshida et al. (U. S. Pub. No. 20030176939) is entitled "Manufacturing system, measurement data collecting system, and measurement terminal apparatus".

Contact Information

6. Any inquiry concerning this communication or earlier communications from the examiner should be directed to Xiuqin Sun whose telephone number is (571)272-2280. The examiner can normally be reached on 6:30am-4:00pm.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, John Barlow can be reached on (571)272-2269. The fax phone number for the organization where this application or proceeding is assigned is 703-872-9306.


Art Unit: 2863

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see <http://pair-direct.uspto.gov>. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

XS
XS

January 5, 2005

Xiuqin Sun
Examiner
Art Unit 2863


John Carlow
Supervisory Patent Examiner
Technology Center 2800

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 243329US2		SERIAL NO. New Application	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Kenichi KADOTA			
				FILING DATE Herewith		GROUP	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
	AO	2002-323924	11/08/02	Japan (with English Abstract)			x
	AP						
	AQ						
	AR						
	AS						
	AT						
	AU						
	AV						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
XS	AW	Laura PETERS, "Graphically Analyzing Yield Loss", SEMICONDUCTOR INTERNATIONAL, October 1998, page 54					
	AX						
	AY						
	AZ						<input type="checkbox"/> Additional References sheet(s) attached
Examiner <i>ming - Su</i>					Date Considered <i>9/24/05</i>		
<small>*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small>							

Notice of References Cited	Application/Control No. 10/670,330	Applicant(s)/Patent Under Reexamination KADOTA, KENICHI	
	Examiner Xiuqin Sun	Art Unit 2863	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,274,434	12-1993	Morioka et al.	356/237.4
	B	US-5,726,920	03-1998	Chen et al.	702/108
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

BEST AVAILABLE COPY



5 02 1A \$01.98⁰
0004204034 JAN 24 2005
MAILED FROM ZIP CODE 22314

COMMISSIONER FOR PATENTS

P.O. BOX 1450

ALEXANDRIA, VA 22313-1450

IF UNDELIVERABLE RETURN IN TEN DAYS

OFFICIAL BUSINESS

AN EQUAL OPPORTUNITY EMPLOYER

228511

7590

01/25/2005

OBLON, SPIVAK, MCCLELLAND, MAIER & NEUSTADT, P.C.

1940 DUKE STREET

ALEXANDRIA, VA 22314

RECEIVED

FFB 10 2005

TECHNOLOGY CENTER 2800

Serial No. 10/670,330

Exhibit B

File Edit Explorer Reports Tools Window Help

Patent Case Information for Docket #: 243329US-2348-39-2, Application #: 10/670,330, PTO Mail: 06/02/2005 REJECTION

General Case Information

- Actions
- Inventors
- Clients/Entities
- Attorneys
- Assignments
- File Folders
- Incoming Mail Track Entries
- Outgoing Correspondence
- PTO Mail
 - 10/07/2003 ADV SNC
 - 12/29/2003 OFR
 - 12/29/2003 NFMP
 - 03/15/2004 OFR (Corrected)
 - 08/24/2004 RCRD ASSGN
 - 02/07/2005 Patent Notice of Publication
 - 06/02/2005 REJECTION**
- Images
- Filing Receipts
- Parent Cases
- Children Cases
- Specification Information
- Terminal Disclaimers
- PTO Filings
- Incoming Correspondence
- Search Reports
- Cited References (Cited by PTO)
- Cited References (Disclosed by Applicant)

PTO Mail

PTO Mail ID: 6861346

Case ID: 243628-US

Mail Type: REJECTION

Description:

Date Received: 06/02/2005

Base Date: 01/21/2005

Corrected: ☐ Fax: ☐

Duplicate: ☐ Reset: ☐ E-Mailed: ☐

Remarks: Rcvd via PAIR Printout 6/2/05

Ready 06/08/2005 8:55:21 AM

PTO Mail Log Report

From 01/21/2005 to 02/04/2005

Exhibit C

Mail Type	C,D,F,R	Application #	Patent#/Reg#	Case Id	Base Date	Date Rcvd
REJECTION		09/576,037		161903US	01-18-2005	01-21-2005
REJECTION		09/706,783		199322US	01-19-2005	01-21-2005
REJECTION		09/813,751		252533US	01-18-2005	01-21-2005
REJECTION		09/878,343		209426US	01-19-2005	01-21-2005
REJECTION		09/907,948		211470US	01-18-2005	01-21-2005
REJECTION		09/920,737		212288US	01-19-2005	01-21-2005
REJECTION		09/996,903		205994US	01-19-2005	01-21-2005
REJECTION		10/022,771		217364US	01-18-2005	01-21-2005
REJECTION		10/090,747		220362US	01-21-2005	01-21-2005
REJECTION		10/107,318		221249US	01-19-2005	01-21-2005
REJECTION		10/220,284		227754US	01-18-2005	01-21-2005
REJECTION		10/265,253		228803US	01-19-2005	01-21-2005
REJECTION		10/266,581		229040US	01-19-2005	01-21-2005
REJECTION		10/391,898		234897US	01-18-2005	01-21-2005
REJECTION		10/399,786		234174US	01-19-2005	01-21-2005
REJECTION		10/494,729		252345US	01-19-2005	01-21-2005
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REJECTION		10/965,774		260343US	01-18-2005	01-21-2005
REJECTION		09/943,518		213391US	01-21-2005	01-24-2005
REJECTION		10/083,385		220049US	01-21-2005	01-24-2005
REJECTION		10/085,056		220081US	01-21-2005	01-24-2005
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REJECTION		10/297,596		231354US	01-21-2005	01-24-2005
REJECTION		10/317,068		231598US	01-21-2005	01-24-2005
REJECTION		10/351,479		233339US	01-21-2005	01-24-2005
REJECTION		10/357,391		233124US	01-21-2005	01-24-2005

PTO Mail Log Report

From 01/21/2005 to 02/04/2005

Mail Type	G,D,F,R	Application #	Patent #/Reg #	Case Id	Base Date	Date Rcvd
REJECTION		10/366,457		233087US	01-21-2005	01-24-2005
REJECTION		10/393,067		225221US	01-21-2005	01-24-2005
REJECTION		10/403,076		236054US	01-21-2005	01-24-2005
REJECTION		10/410,153		236409US	01-21-2005	01-24-2005
REJECTION		10/416,529		238021US	01-21-2005	01-24-2005
REJECTION		10/467,344		241651US	01-21-2005	01-24-2005
REJECTION		10/649,704		241998US	01-21-2005	01-24-2005
REJECTION		10/683,046		243977US	01-21-2005	01-24-2005
REJECTION		10/702,488		245198US	01-21-2005	01-24-2005
REJECTION		10/921,257		252509US	01-21-2005	01-24-2005
REJECTION		09/640,068		196078US	01-24-2005	01-25-2005
REJECTION		09/713,194		199688US	01-24-2005	01-25-2005
REJECTION		09/880,062		209852US	01-24-2005	01-25-2005
REJECTION		10/030,141		217772US	01-24-2005	01-25-2005
REJECTION		10/059,227		219058US	01-24-2005	01-25-2005
REJECTION		10/067,241		219196US	01-24-2005	01-25-2005
REJECTION		10/176,609		224015US	01-24-2005	01-25-2005
REJECTION		10/315,039		231582US	01-24-2005	01-25-2005
REJECTION		10/369,723		234225US	01-24-2005	01-25-2005
REJECTION		10/472,554		242913US	01-24-2005	01-25-2005
REJECTION		09/918,477		211929US	01-25-2005	01-26-2005
REJECTION		10/070,443		221014US	01-25-2005	01-26-2005
REJECTION		10/321,377		232017US	01-25-2005	01-26-2005
REJECTION		10/350,125		232283US	01-25-2005	01-26-2005
REJECTION		10/369,667		232899US	01-24-2005	01-26-2005
REJECTION		10/415,338		236528US	01-25-2005	01-26-2005
REJECTION		10/450,154		237784US	01-25-2005	01-26-2005
REJECTION		10/491,432		251367US	01-25-2005	01-26-2005
REJECTION		09/398,038		138698US	01-25-2005	01-27-2005
REJECTION		09/662,116		197329US	01-25-2005	01-27-2005
REJECTION		09/879,043		209543US	01-26-2005	01-27-2005
REJECTION		09/900,609		257367US	01-25-2005	01-27-2005
REJECTION		09/926,511		215653US	01-25-2005	01-27-2005

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REJECTION		09/960,339		214303US	01-26-2005	01-27-2005
REJECTION		10/030,144		218450US	01-25-2005	01-27-2005
REJECTION		10/049,902		218781US	01-25-2005	01-27-2005
REJECTION		10/134,509		222501US	01-25-2005	01-27-2005
REJECTION		10/171,974		221896US	01-25-2005	01-27-2005
REJECTION		10/194,014		225083US	01-25-2005	01-27-2005
REJECTION		10/200,778		225699US	01-25-2005	01-27-2005
REJECTION		10/225,186		226959US	01-25-2005	01-27-2005
REJECTION		10/250,684		238996US	01-25-2005	01-27-2005
REJECTION		10/257,949		228775US	01-25-2005	01-27-2005
REJECTION		10/269,052		222632US	01-25-2005	01-27-2005
REJECTION		10/279,935		229696US	01-25-2005	01-27-2005
REJECTION		10/286,854		230230US	01-25-2005	01-27-2005
REJECTION		10/297,594		231352US	01-21-2005	01-27-2005
REJECTION		10/344,008		233655US	01-25-2005	01-27-2005
REJECTION		10/345,971		232952US	01-25-2005	01-27-2005
REJECTION		10/347,452		232860US	01-25-2005	01-27-2005
REJECTION		10/353,952		214219US	01-26-2005	01-27-2005
REJECTION		10/402,950		236115US	01-25-2005	01-27-2005
REJECTION		10/417,180		236671US	01-25-2005	01-27-2005
REJECTION		10/440,098		237218US	01-25-2005	01-27-2005
S/REJECTION		10/474,038		243451US	01-24-2005	01-27-2005
REJECTION		10/476,372		244518US	01-19-2005	01-27-2005
REJECTION		10/491,434		251760US	01-25-2005	01-27-2005
REJECTION		10/606,750		239522US	01-25-2005	01-27-2005
REJECTION		10/610,652		238602US	01-24-2005	01-27-2005
REJECTION		10/621,387		240468US	01-25-2005	01-27-2005
REJECTION		10/681,205		243895US	01-25-2005	01-27-2005
REJECTION		10/722,512		245842US	01-25-2005	01-27-2005
REJECTION		10/769,849		248163US	01-25-2005	01-27-2005
REJECTION		10/808,322		251000US	01-24-2005	01-27-2005
REJECTION		10/846,623		253080US	01-25-2005	01-27-2005
REJECTION		10/876,665		254480US	01-24-2005	01-27-2005

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REJECTION		09/353,998		203654US	01-26-2005	01-28-2005
REJECTION		09/563,498		111066US	01-26-2005	01-28-2005
REJECTION		09/575,104		203738US	01-27-2005	01-28-2005
REJECTION		09/609,070		194021US	01-26-2005	01-28-2005
REJECTION		09/639,946		142738US	01-26-2005	01-28-2005
REJECTION		09/695,636		203794US	01-27-2005	01-28-2005
REJECTION		09/783,594		203271US	01-26-2005	01-28-2005
REJECTION		09/796,431		202098US	01-26-2005	01-28-2005
REJECTION		09/840,155		202319US	01-26-2005	01-28-2005
REJECTION		09/885,407		210201US	01-26-2005	01-28-2005
REJECTION		09/891,517		210352US	01-26-2005	01-28-2005
REJECTION		09/962,274		213776US	01-26-2005	01-28-2005
REJECTION		09/981,766		215217US	01-26-2005	01-28-2005
REJECTION		09/984,712		215689US	01-26-2005	01-28-2005
REJECTION		10/030,176		218424US	01-25-2005	01-28-2005
REJECTION		10/085,081		220119US	01-26-2005	01-28-2005
REJECTION		10/111,406		222352US	01-26-2005	01-28-2005
REJECTION		10/148,577		223429US	01-26-2005	01-28-2005
REJECTION		10/170,573		224388US	01-26-2005	01-28-2005
REJECTION		10/201,315		225893US	01-26-2005	01-28-2005
REJECTION		10/206,235		225626US	01-26-2005	01-28-2005
REJECTION		10/241,639		227855US	01-26-2005	01-28-2005
REJECTION		10/256,014		228314US	01-26-2005	01-28-2005
REJECTION		10/323,792		232027US	01-26-2005	01-28-2005
REJECTION		10/344,556		232966US	01-26-2005	01-28-2005
REJECTION		10/398,746		236217US	01-26-2005	01-28-2005
REJECTION		10/411,281		236469US	01-26-2005	01-28-2005
REJECTION		10/415,099		236375US	01-26-2005	01-28-2005
REJECTION		10/436,292		237522US	01-26-2005	01-28-2005
REJECTION		10/440,148		237889US	01-26-2005	01-28-2005
REJECTION		10/447,229		237883US	01-26-2005	01-28-2005
REJECTION		10/452,454		238325US	01-26-2005	01-28-2005
REJECTION		10/483,085		247056US	01-27-2005	01-28-2005

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REJECTION		10/486,831		248512US	01-26-2005	01-28-2005
REJECTION		10/627,730		240825US	01-26-2005	01-28-2005
REJECTION		10/670,279		243203US	01-25-2005	01-28-2005
REJECTION		10/868,815		254436US	01-26-2005	01-28-2005
REJECTION		10/911,544		256768US	01-26-2005	01-28-2005
REJECTION		09/686,878		198542US	01-27-2005	01-31-2005
REJECTION		09/691,235		198554US	01-26-2005	01-31-2005
REJECTION		09/716,376		199819US	01-25-2005	01-31-2005
REJECTION		09/728,056		200436US	01-27-2005	01-31-2005
REJECTION		09/808,240		204331US	01-27-2005	01-31-2005
REJECTION		09/813,988		205040US	01-26-2005	01-31-2005
REJECTION		09/832,895		206006US	01-26-2005	01-31-2005
REJECTION		09/879,191		209820US	01-26-2005	01-31-2005
REJECTION		09/894,321		210678US	01-26-2005	01-31-2005
REJECTION		09/930,212		212905US	01-26-2005	01-31-2005
REJECTION		09/984,140		215561US	01-27-2005	01-31-2005
REJECTION		09/987,881		216231US	01-26-2005	01-31-2005
REJECTION		10/002,693		263552US	01-06-2005	01-31-2005
REJECTION		10/014,670		216907US	01-27-2005	01-31-2005
REJECTION		10/073,297		219451US	01-27-2005	01-31-2005
REJECTION		10/085,732		220147US	01-25-2005	01-31-2005
REJECTION		10/102,849		221042US	01-26-2005	01-31-2005
REJECTION		10/169,101		225429US	01-27-2005	01-31-2005
REJECTION		10/187,015		225109US	01-27-2005	01-31-2005
REJECTION		10/227,818		227469US	01-26-2005	01-31-2005
REJECTION		10/263,841		229127US	01-26-2005	01-31-2005
REJECTION		10/311,318		232279US	01-27-2005	01-31-2005
REJECTION		10/319,506		202922US	01-26-2005	01-31-2005
REJECTION		10/333,907		232444US	01-26-2005	01-31-2005
REJECTION		10/335,846		232588US	01-27-2005	01-31-2005
REJECTION		10/341,467		232809US	01-27-2005	01-31-2005
REJECTION		10/384,596		234896US	01-27-2005	01-31-2005
REJECTION	D	10/393,067		225221US	01-21-2005	01-31-2005

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REJECTION		10/420,755		237045US	01-26-2005	01-31-2005
REJECTION		10/448,412		237385US	01-26-2005	01-31-2005
REJECTION		10/609,401		239707US	01-27-2005	01-31-2005
REJECTION		10/639,627		241469US	01-28-2005	01-31-2005
REJECTION		10/659,310		242629US	01-27-2005	01-31-2005
REJECTION		10/665,154		243006US	01-27-2005	01-31-2005
REJECTION		10/679,493		242773US	01-27-2005	01-31-2005
REJECTION		10/693,891		244709US	01-27-2005	01-31-2005
REJECTION		10/699,676		244838US	01-26-2005	01-31-2005
REJECTION		10/712,037		245403US	01-27-2005	01-31-2005
REJECTION		10/714,475		244809US	01-27-2005	01-31-2005
REJECTION		10/720,126		245838US	01-28-2005	01-31-2005
REJECTION		10/753,338		246924US	01-27-2005	01-31-2005
REJECTION		10/787,413		249344US	01-27-2005	01-31-2005
REJECTION		10/793,849		249912US	01-27-2005	01-31-2005
REJECTION		10/891,155		255137US	01-28-2005	01-31-2005
REJECTION		09/459,574		163728US	01-27-2005	02-01-2005
REJECTION		09/797,872		203926US	01-28-2005	02-01-2005
REJECTION		09/985,757		215686US	01-28-2005	02-01-2005
REJECTION		10/127,754		222447US	01-27-2005	02-01-2005
REJECTION		10/246,411		227530US	01-24-2005	02-01-2005
REJECTION		10/389,751		235422US	01-28-2005	02-01-2005
REJECTION		10/418,112		236709US	01-28-2005	02-01-2005
REJECTION		10/612,146		239799US	01-28-2005	02-01-2005
REJECTION		10/614,033		239929US	01-31-2005	02-01-2005
REJECTION		10/651,986		241961US	01-28-2005	02-01-2005
REJECTION		10/653,098		242221US	01-28-2005	02-01-2005
REJECTION		10/748,149		246323US	01-27-2005	02-01-2005
REJECTION		09/606,885		203761US	01-31-2005	02-02-2005
REJECTION		09/874,057		209396US	01-31-2005	02-02-2005
REJECTION		09/889,557		211526US	01-31-2005	02-02-2005
REJECTION		09/985,482		215814US	01-31-2005	02-02-2005
REJECTION		10/069,599		220188US	01-27-2005	02-02-2005

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REJECTION		10/098,143		220671US	02-01-2005	02-02-2005
REJECTION		10/110,782		222240US	02-01-2005	02-02-2005
REJECTION		10/220,298		227995US	01-28-2005	02-02-2005
REJECTION		10/230,999		219430US	02-01-2005	02-02-2005
REJECTION		10/288,366		230343US	01-31-2005	02-02-2005
REJECTION		10/307,976		231304US	02-01-2005	02-02-2005
REJECTION		10/376,628		234514US	02-01-2005	02-02-2005
REJECTION		10/381,438		235377US	01-31-2005	02-02-2005
REJECTION		10/389,988		235330US	02-01-2005	02-02-2005
REJECTION		10/482,406		246932US	01-31-2005	02-02-2005
REJECTION		10/482,807		246880US	02-01-2005	02-02-2005
REJECTION		10/485,253		247565US	02-01-2005	02-02-2005
REJECTION		10/488,293		249920US	02-01-2005	02-02-2005
REJECTION		10/612,985		239861US	02-01-2005	02-02-2005
REJECTION		10/638,401		241422US	01-28-2005	02-02-2005
REJECTION		10/644,728		241563US	01-31-2005	02-02-2005
REJECTION		10/650,714		242002US	01-31-2005	02-02-2005
REJECTION		10/673,155		243317US	01-31-2005	02-02-2005
REJECTION		10/694,875		244665US	01-31-2005	02-02-2005
REJECTION		10/737,121		246602US	01-31-2005	02-02-2005
REJECTION		10/845,656		257363US	01-31-2005	02-02-2005
REJECTION		10/868,353		254040US	01-31-2005	02-02-2005
REJECTION		09/941,680		212557US	02-02-2005	02-03-2005
REJECTION	D	10/002,693		263552US	01-06-2005	02-03-2005
REJECTION		10/334,990		232054US	02-02-2005	02-03-2005
REJECTION		10/362,360		233745US	02-02-2005	02-03-2005
REJECTION		10/381,589		236016US	02-01-2005	02-03-2005
REJECTION		10/389,779		235570US	02-02-2005	02-03-2005
REJECTION		10/396,518		235744US	02-02-2005	02-03-2005
REJECTION		10/400,564		235939US	02-03-2005	02-03-2005
REJECTION		10/426,810		232725US	02-03-2005	02-03-2005
REJECTION		10/474,619		243871US	02-02-2005	02-03-2005
REJECTION		10/480,257		245746US	02-02-2005	02-03-2005

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REJECTION		10/486,828		249202US	02-01-2005	02-03-2005
REJECTION		10/689,680		244104US	02-01-2005	02-03-2005
REJECTION		10/787,135		249404US	02-02-2005	02-03-2005
REJECTION		10/913,531		256351US	02-02-2005	02-03-2005
REJECTION		09/493,192		110905US	02-03-2005	02-04-2005
REJECTION		09/641,917		196197US	02-02-2005	02-04-2005
REJECTION		09/725,511		197792US	02-03-2005	02-04-2005
REJECTION		09/725,515		200133US	02-04-2005	02-04-2005
REJECTION		09/893,667		210683US	02-02-2005	02-04-2005
REJECTION		09/959,745		215777US	01-31-2005	02-04-2005
REJECTION		10/031,569		217865US	02-03-2005	02-04-2005
REJECTION		10/066,565		219294US	02-03-2005	02-04-2005
REJECTION		10/110,206		222004US	02-03-2005	02-04-2005
REJECTION		10/183,515		223448US	02-02-2005	02-04-2005
REJECTION		10/239,208		228679US	02-03-2005	02-04-2005
REJECTION		10/317,123		231568US	02-03-2005	02-04-2005
REJECTION		10/455,431		238694US	02-02-2005	02-04-2005
REJECTION		10/468,824		241471US	02-03-2005	02-04-2005
REJECTION		10/472,199		243131US	02-02-2005	02-04-2005
REJECTION		10/476,499		243833US	02-03-2005	02-04-2005
REJECTION		10/480,250		246477US	02-03-2005	02-04-2005
REJECTION		10/697,287		244440US	02-03-2005	02-04-2005
REJECTION		10/828,416		252144US	02-03-2005	02-04-2005
REJECTION		10/863,366		253131US	02-03-2005	02-04-2005
REJECTION		10/863,753		254627US	01-28-2005	02-04-2005
REJECTION		10/885,578		254648US	02-02-2005	02-04-2005